

Reticular Graphene Reinforced Copper for Electromagnetic Shielding Application

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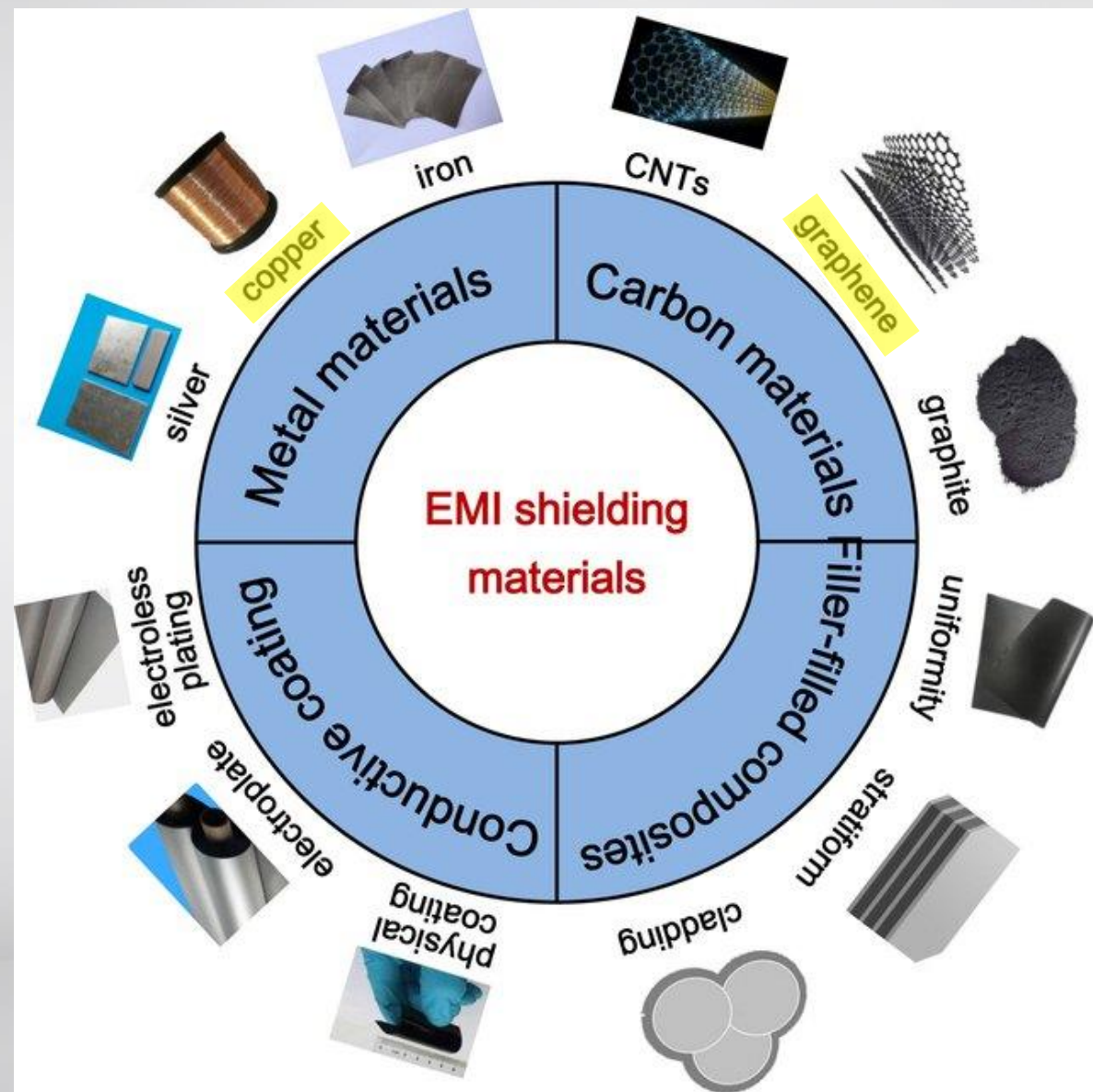
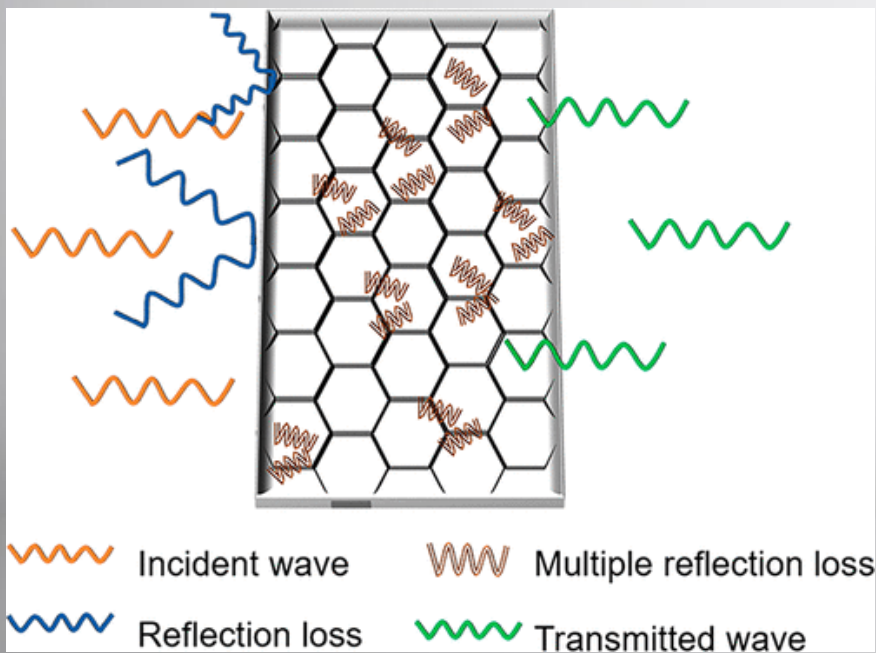
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Electromagnetic Interference (EMI) Shielding



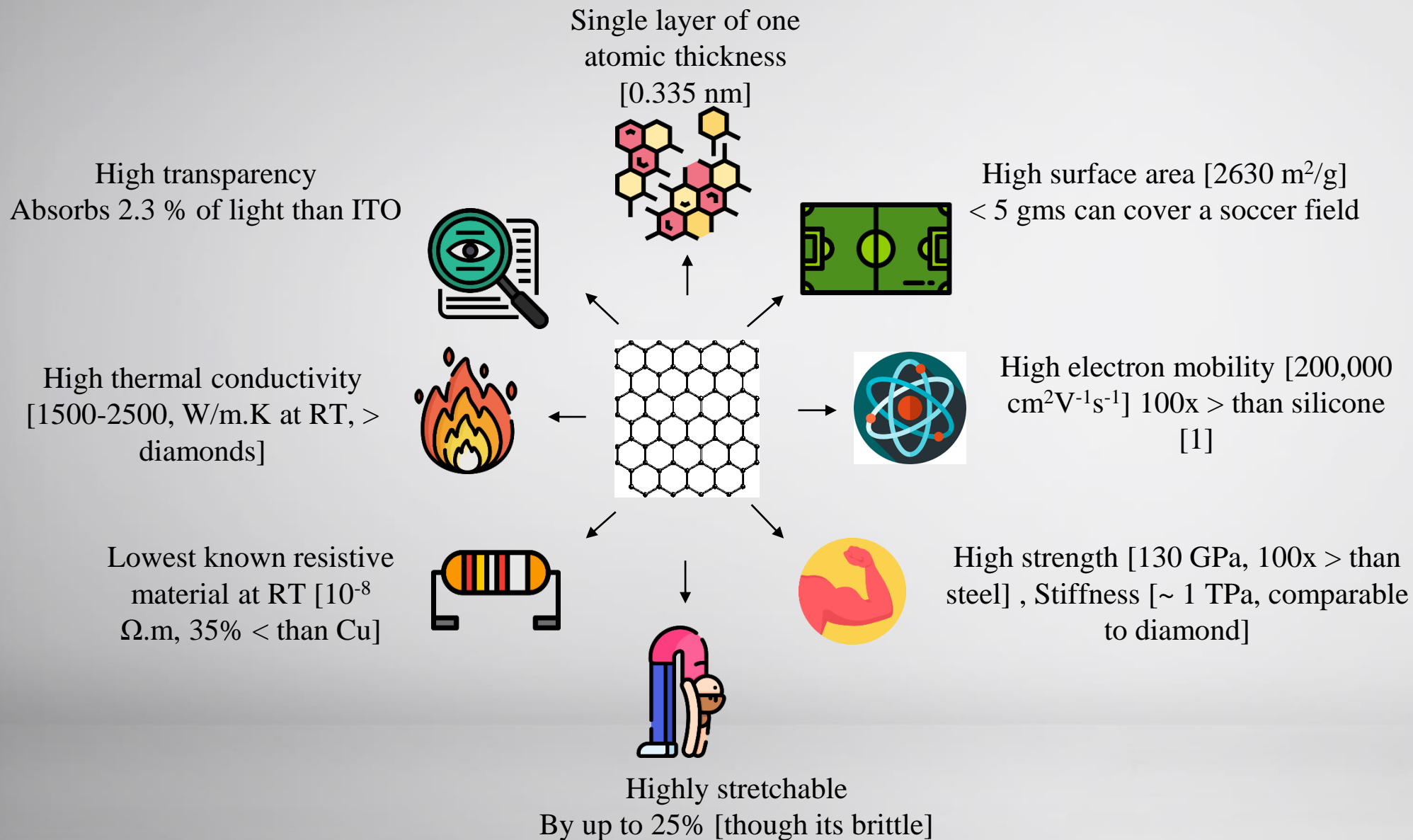
4th major hazard to human survival



Properties of Graphene (Gr)



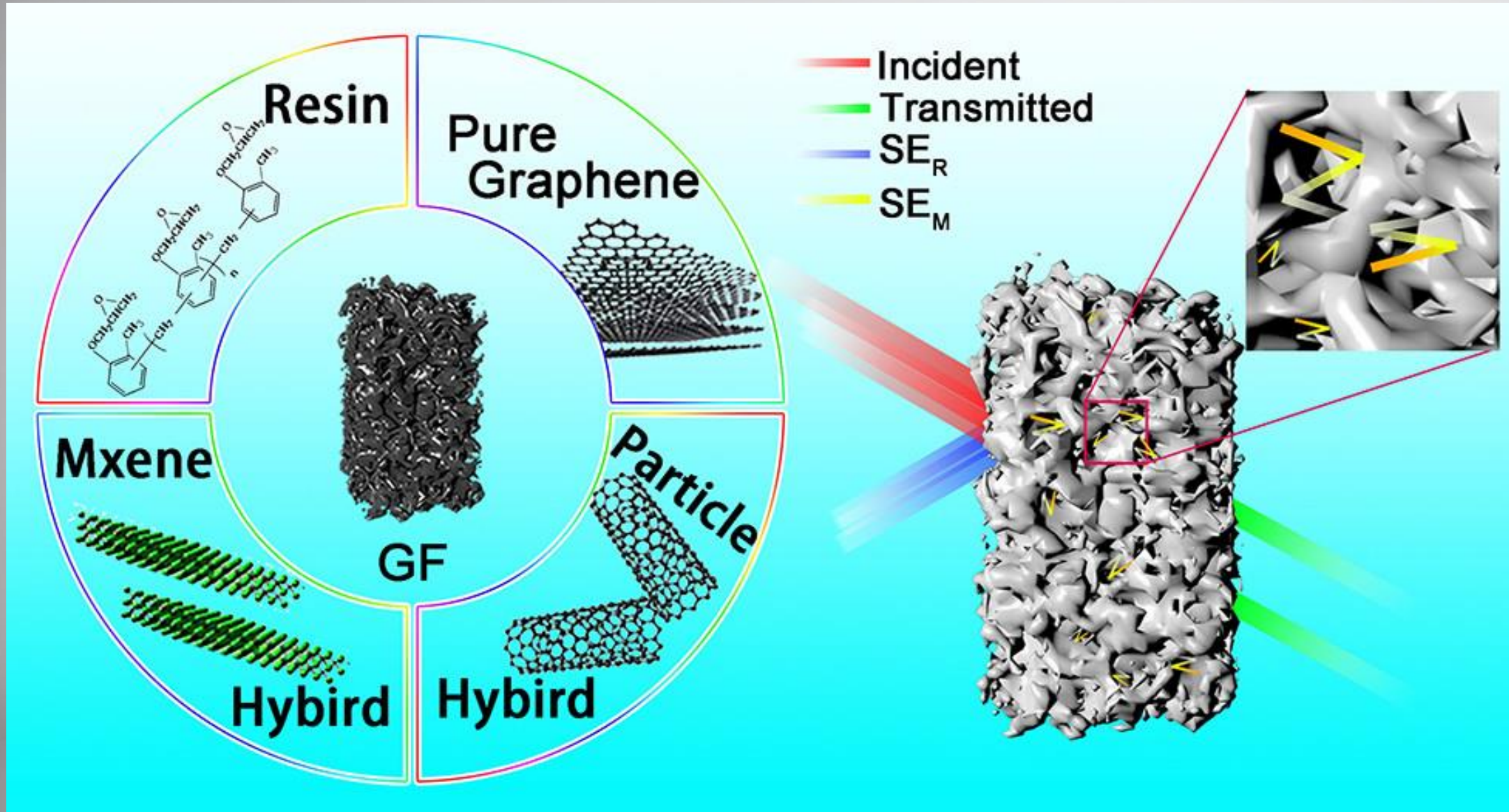
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LABORATORY



Why Gr Foam (GrF)?

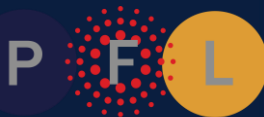


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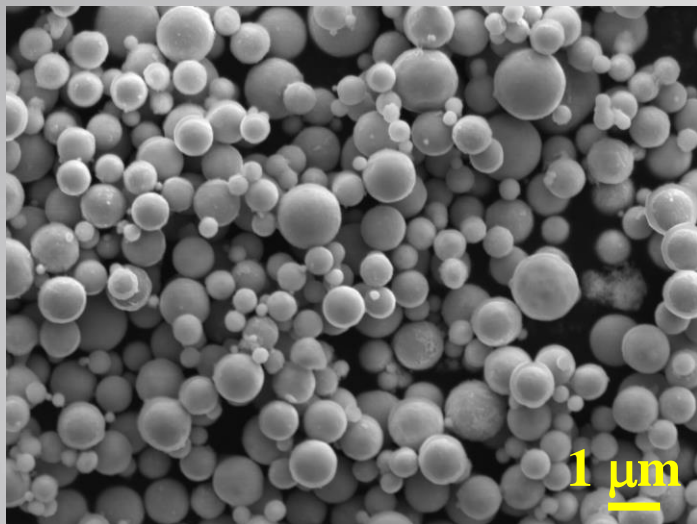
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Starting Materials

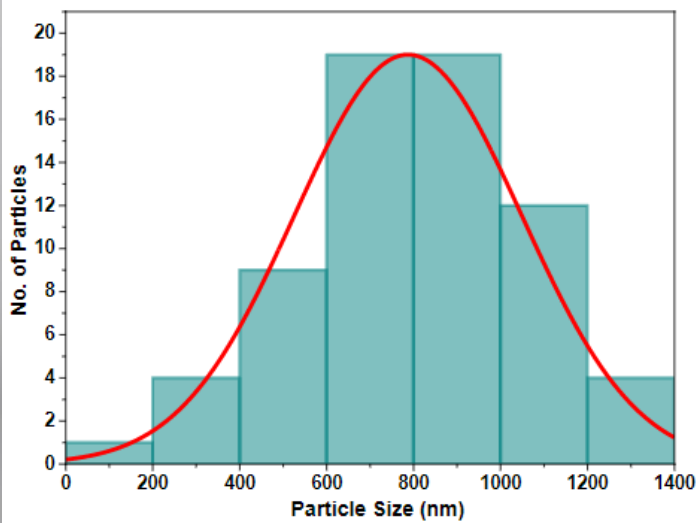


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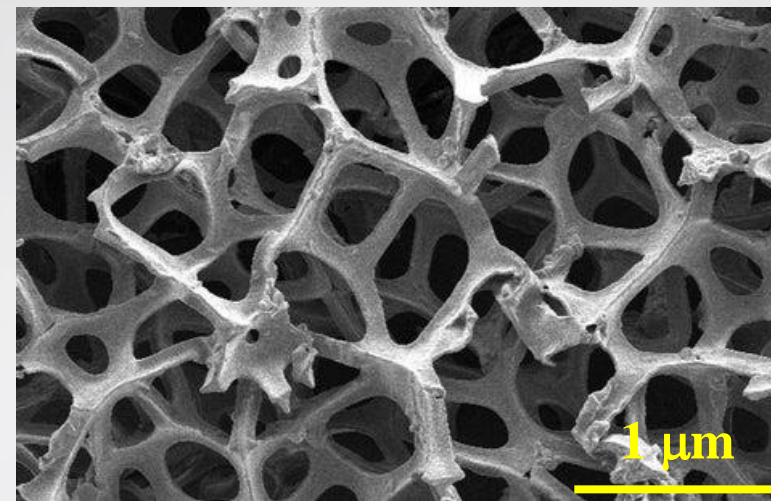
Sub-micron Cu powder



Mean Particle Size: 787 ± 261 nm



Ultra-Light Freestanding 3D Graphene Foams

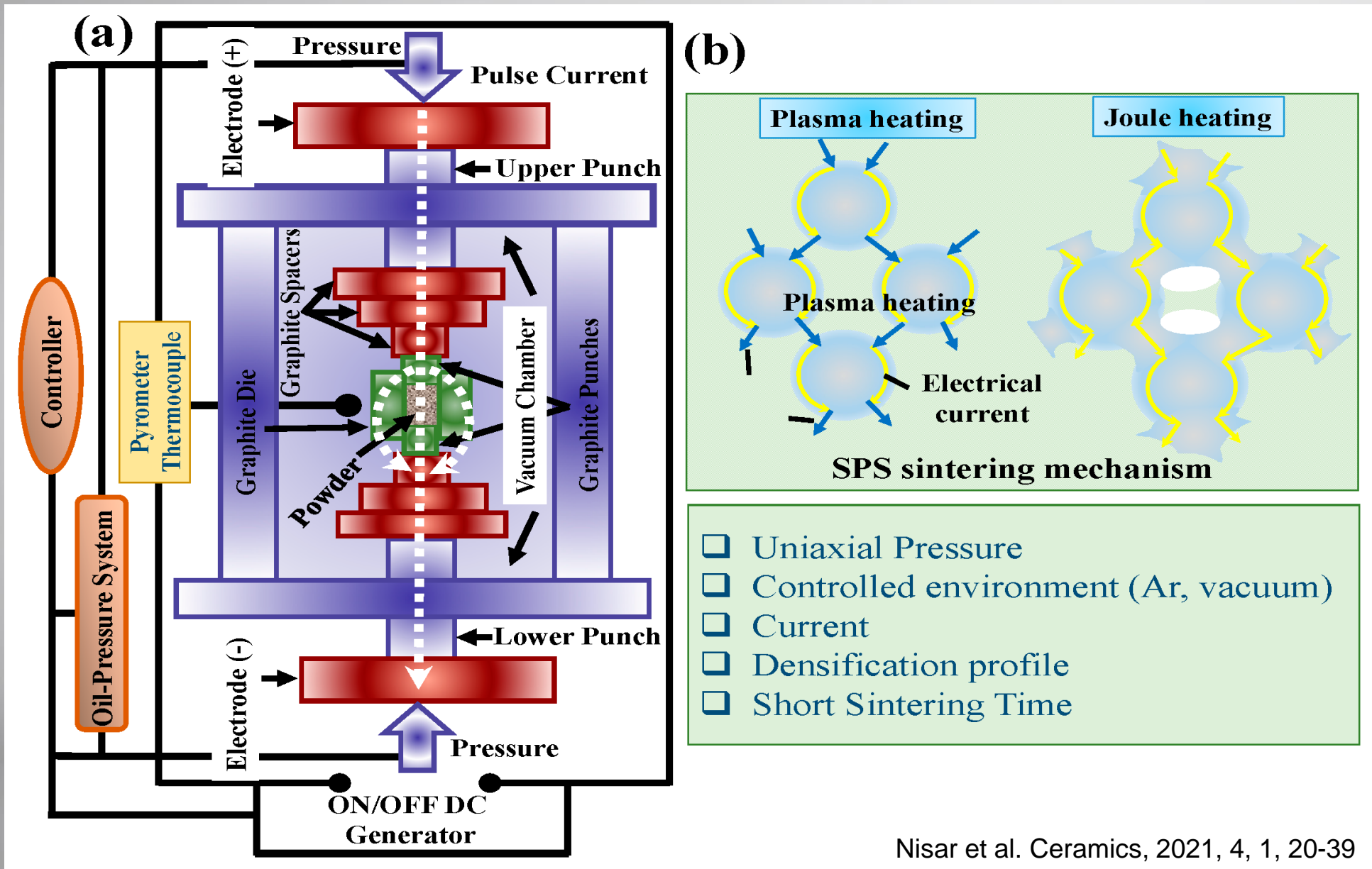


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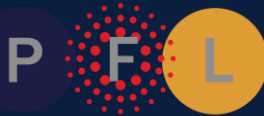
CNPC powder North America Inc., BC, Canada

<https://graphene-supermarket.com/3D-Graphene-Foams/>

Processing via Spark Plasma Sintering (SPS)



Cu decorated GrF



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Dip coating

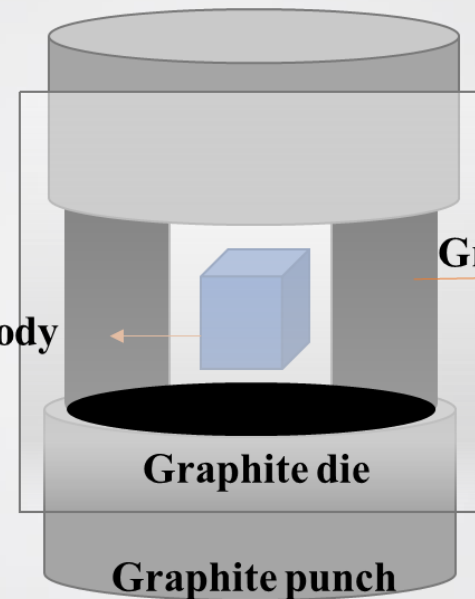
Cu slurry



Air Drying



Green body



Graphite crucible

Graphite die

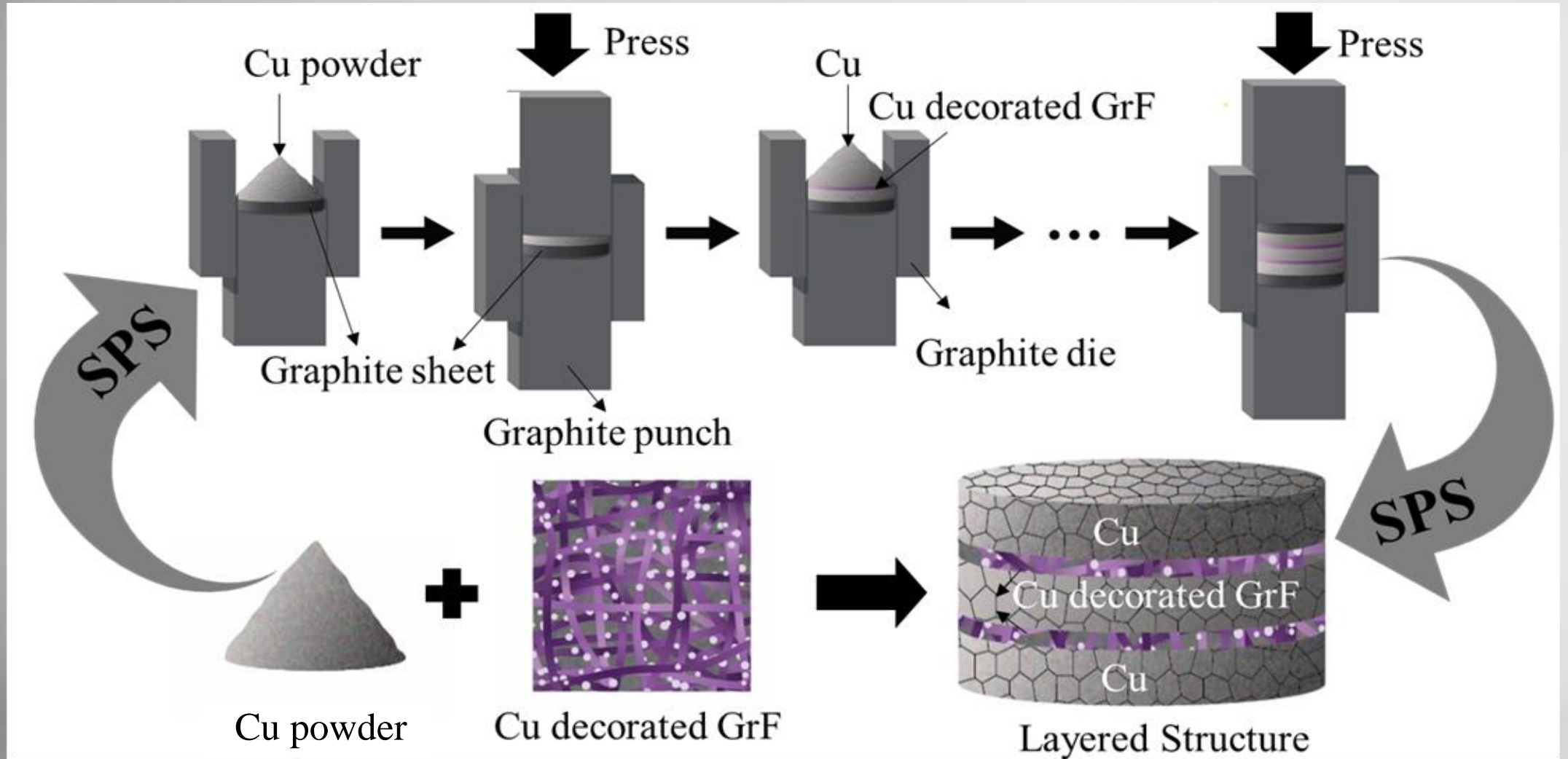
Graphite punch

Pressureless SPS

Process Scheme of Layered Architecture



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Adapted from Nisar et al. accepted in Carbon, 2023

Processing Parameters

Processing details:

- Spark Plasma Sintering
- Temperature : 950 °C, Time: 10 min
- Vacuum environment
- Heating rate : 100 °C/min

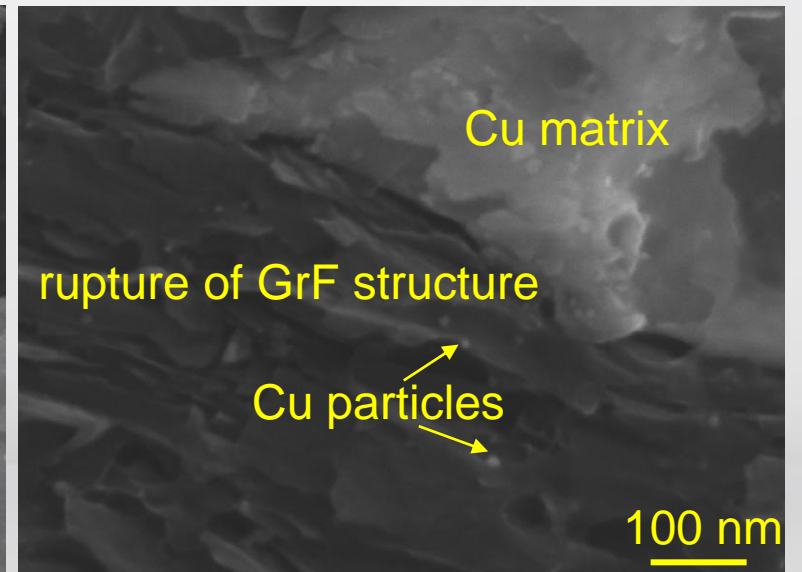
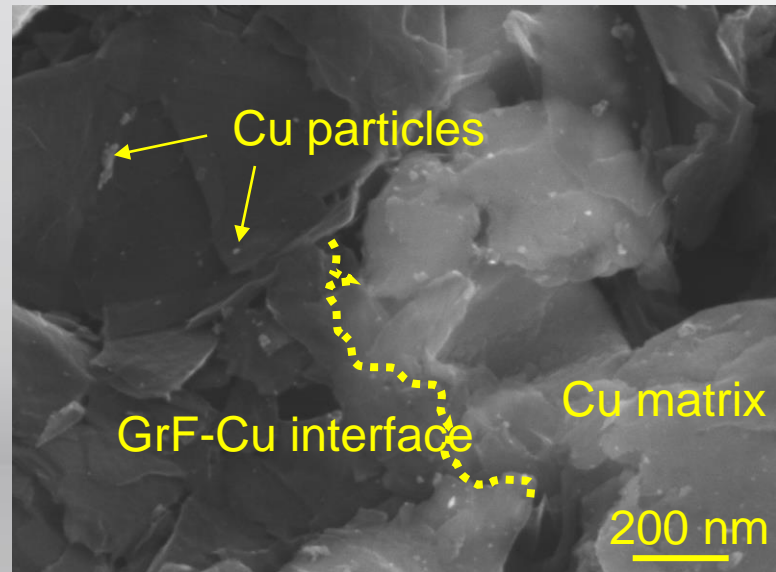
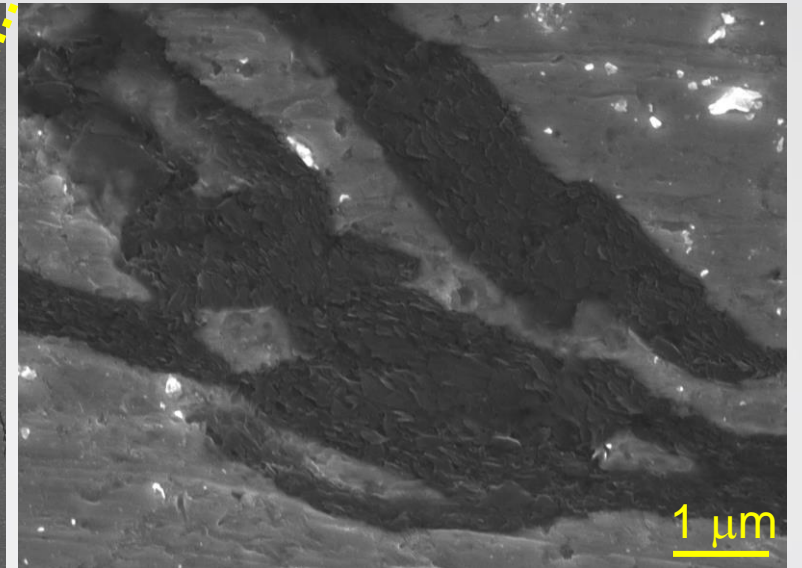
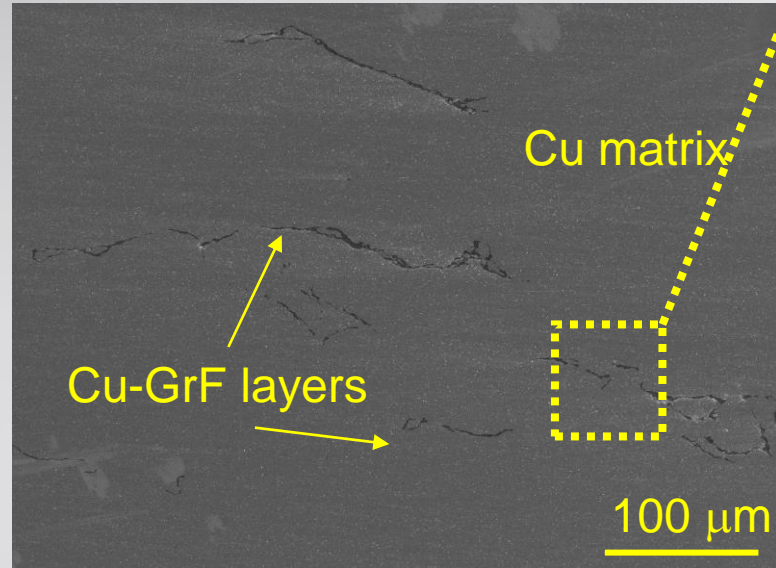
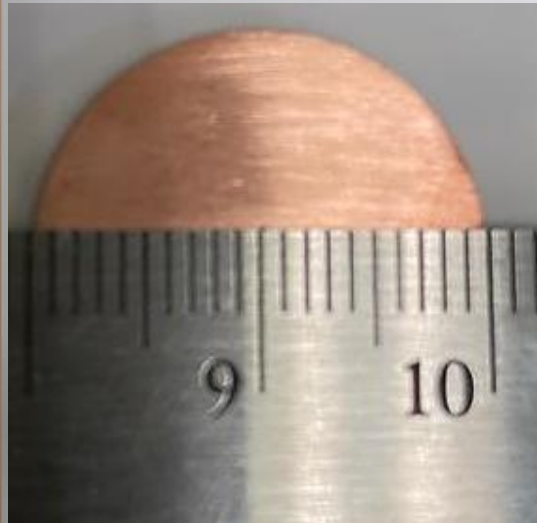
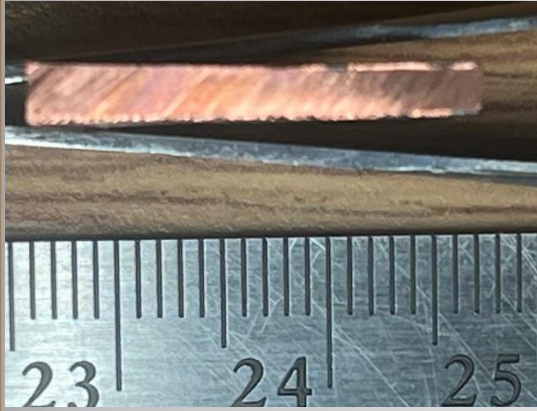
The reticulated structures of GrF-reinforced Cu matrix composites:

- (i) Sintered Cu decorated GrF sandwiched between Cu powder bed at a pressure of 5 MPa.
- (ii) Sintered Cu decorated GrF sandwiched between Cu powder bed without pressure.

Approach 1: With Pressure

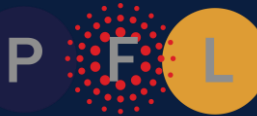


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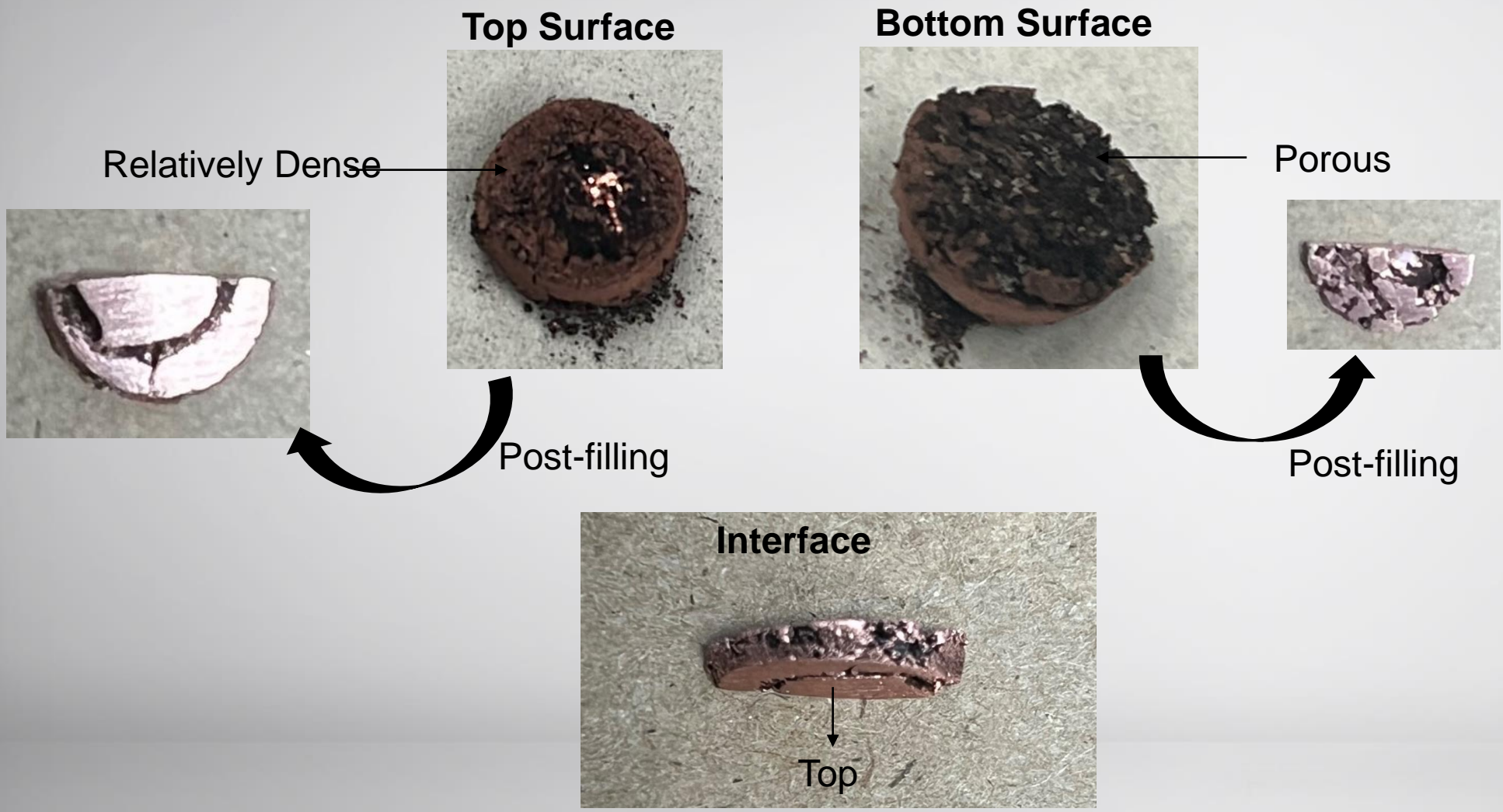


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Approach 2: Without Pressure

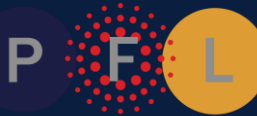


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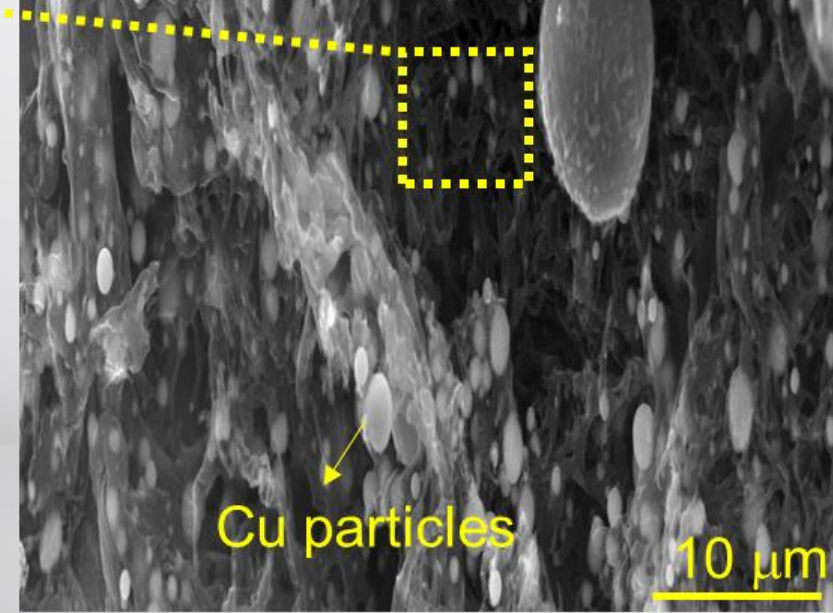
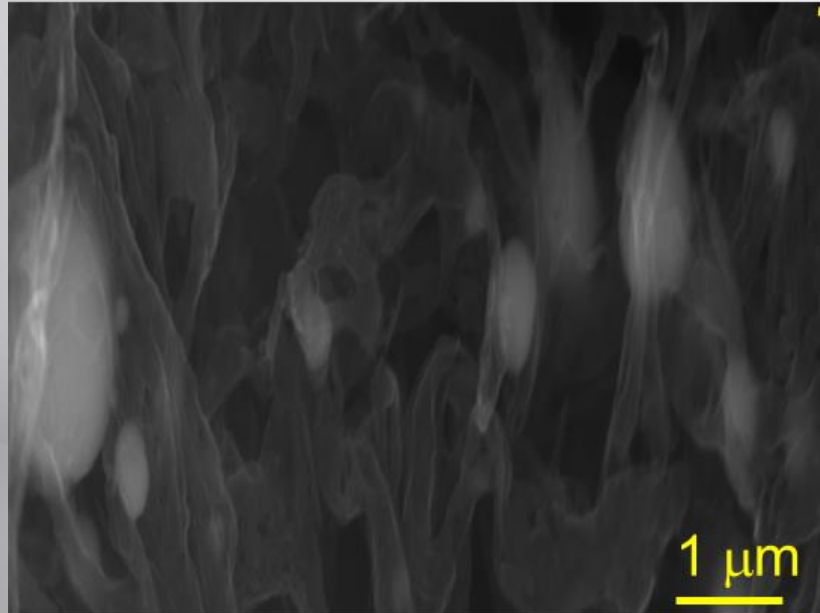
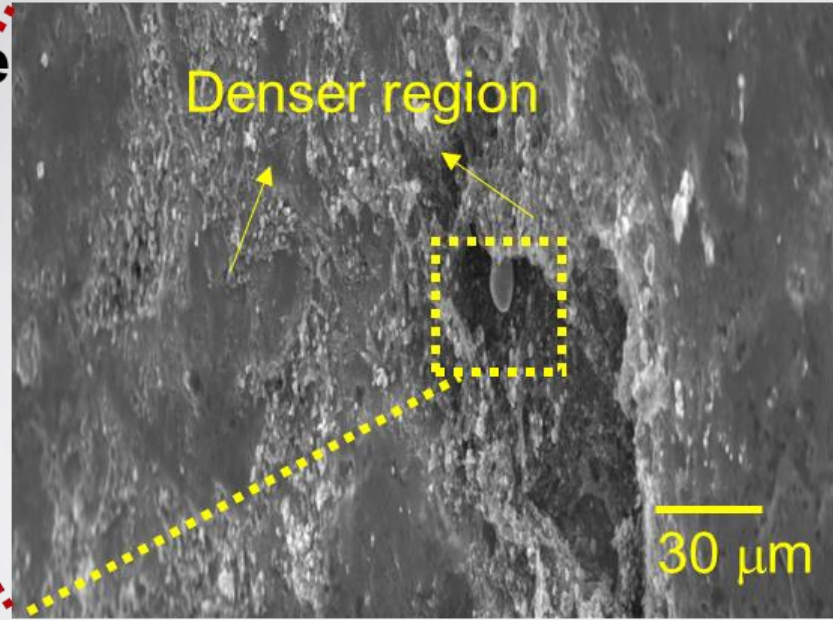
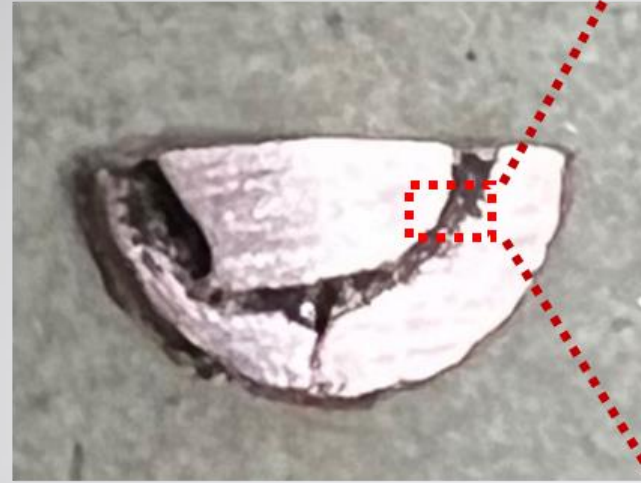
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Microstructural Analysis of Dense Cu-GrF



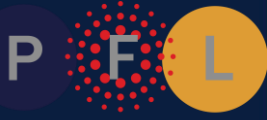
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(a) Top Dense-Surface



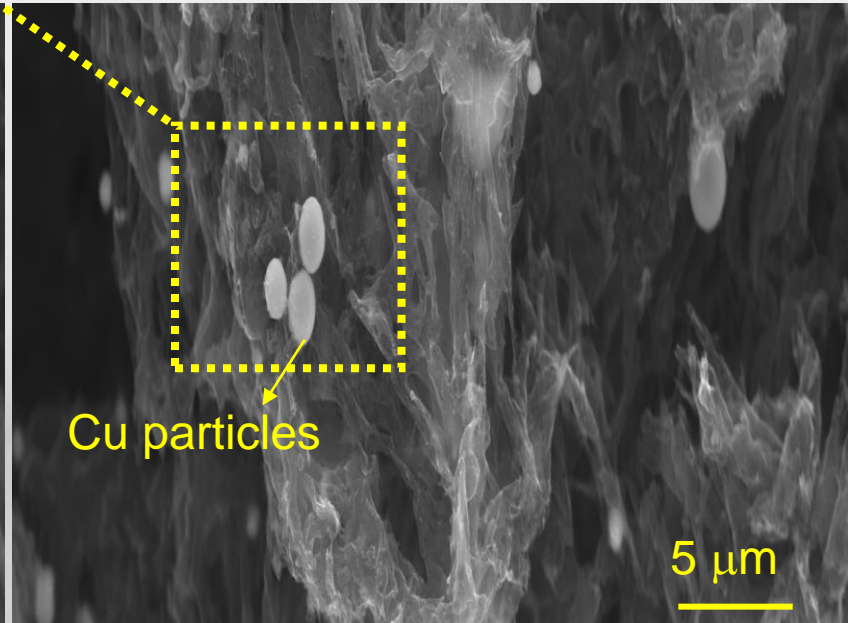
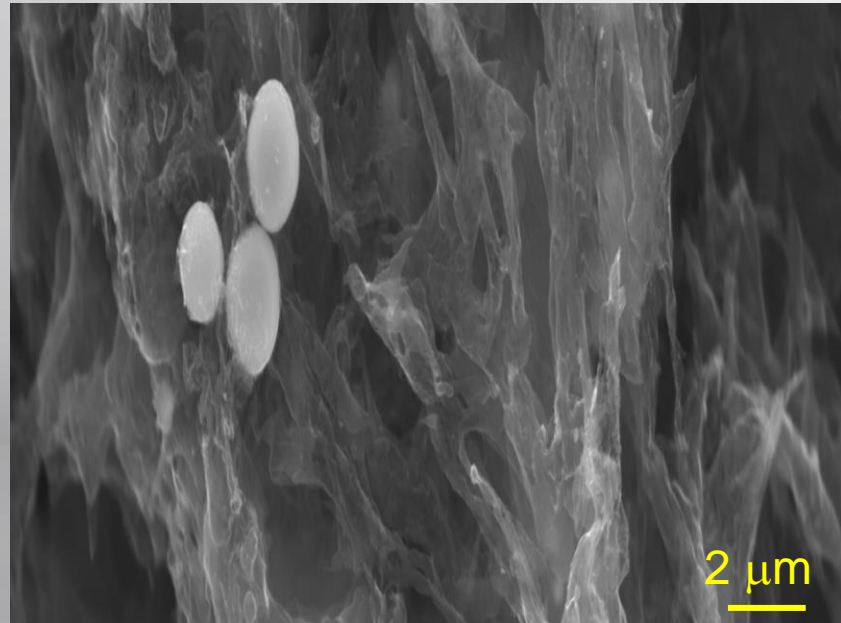
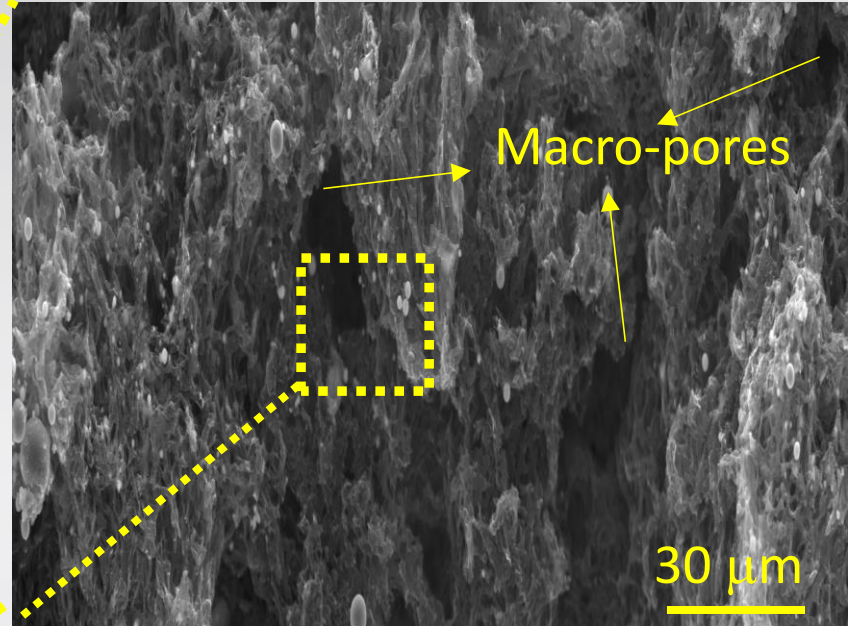
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Microstructural Analysis of Porous Cu-GrF



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(b) Bottom Porous-Surface



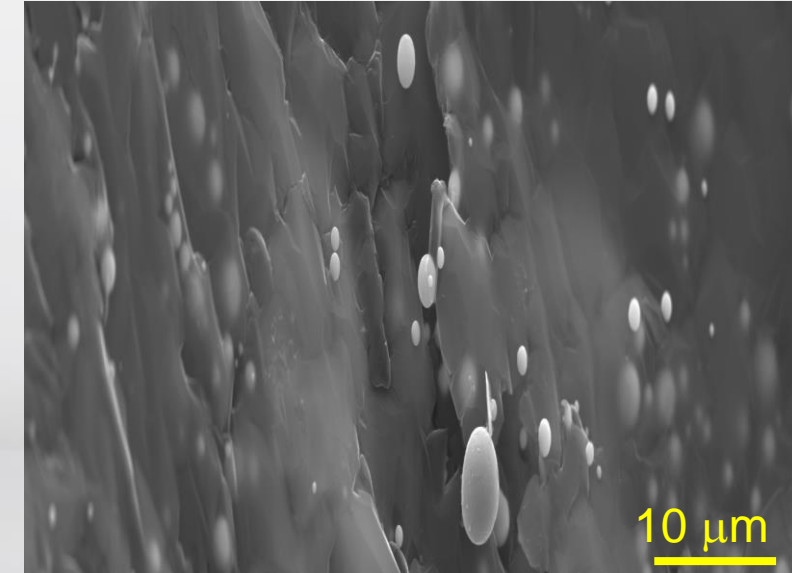
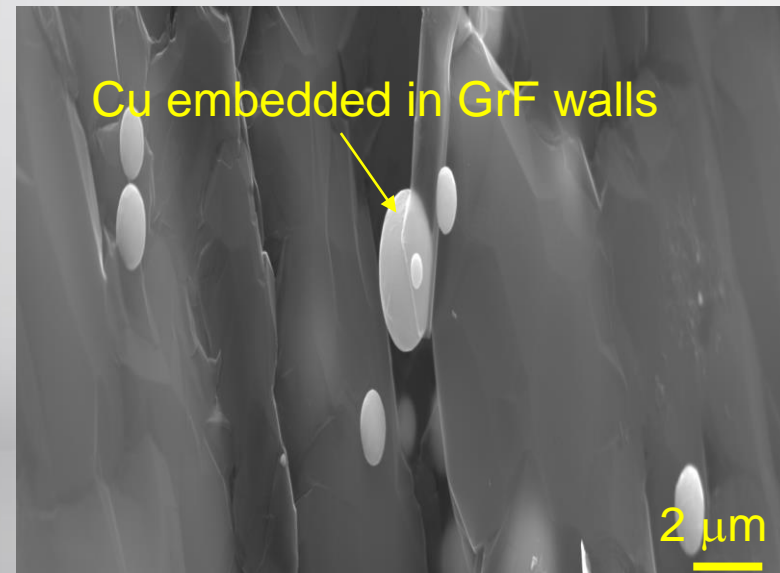
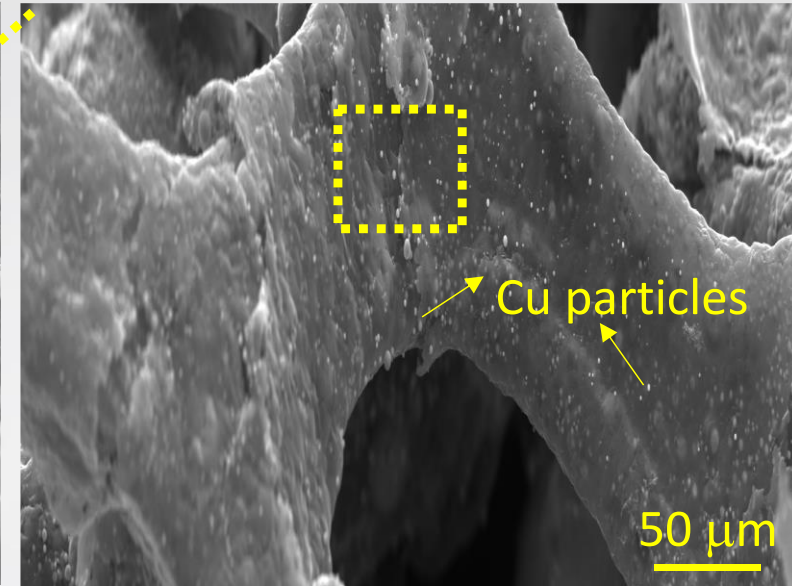
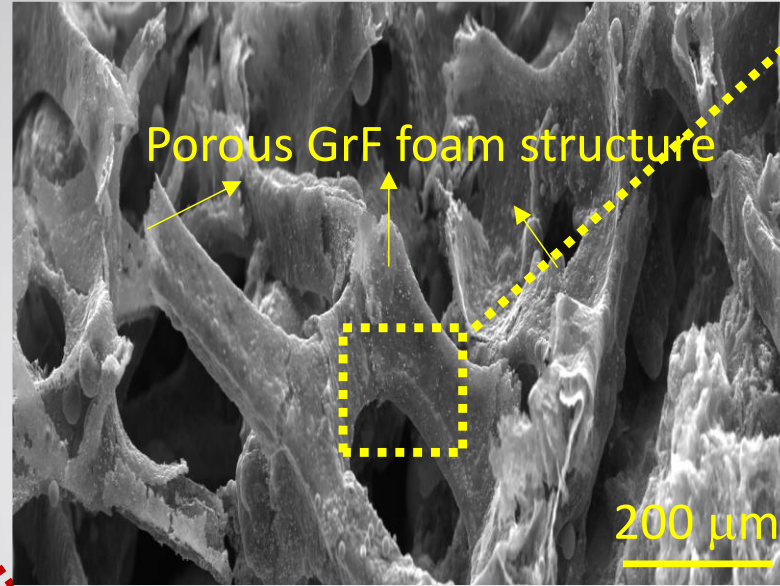
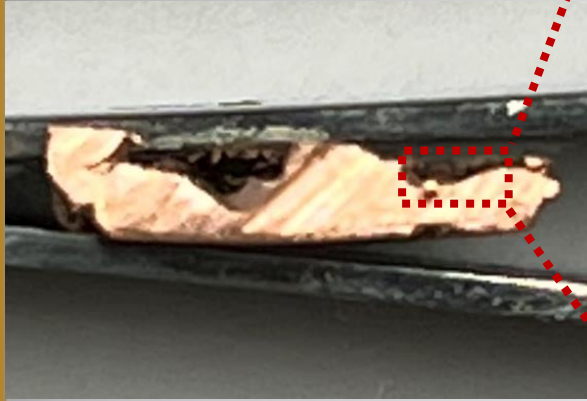
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Microstructural Analysis of Cu-GrF Interface



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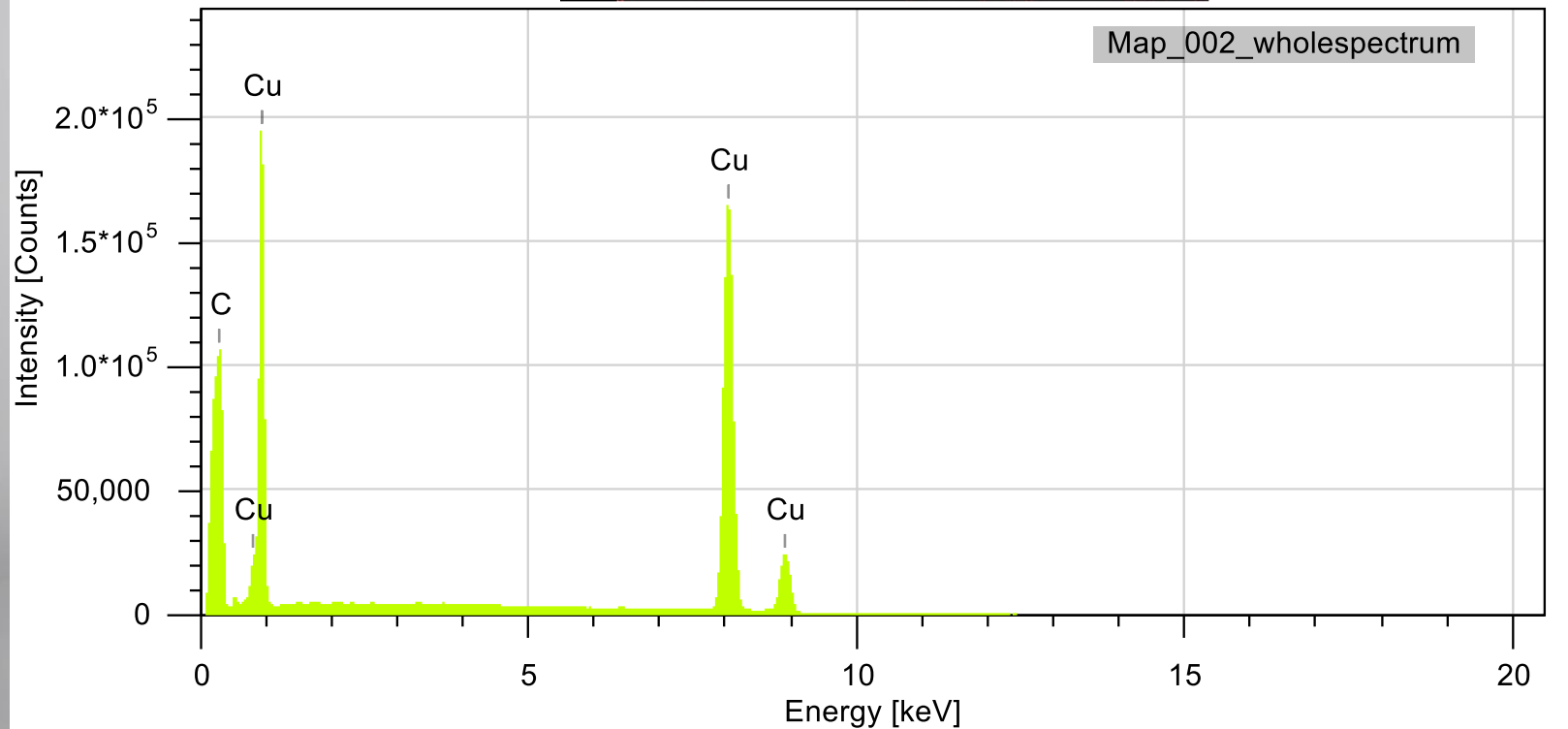
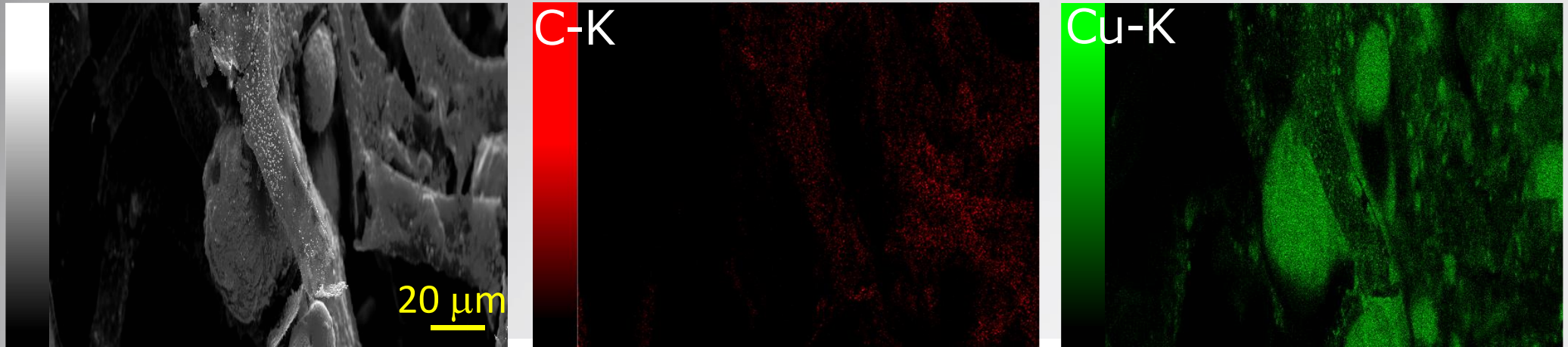
(c) Cross-section



Compositional Analysis



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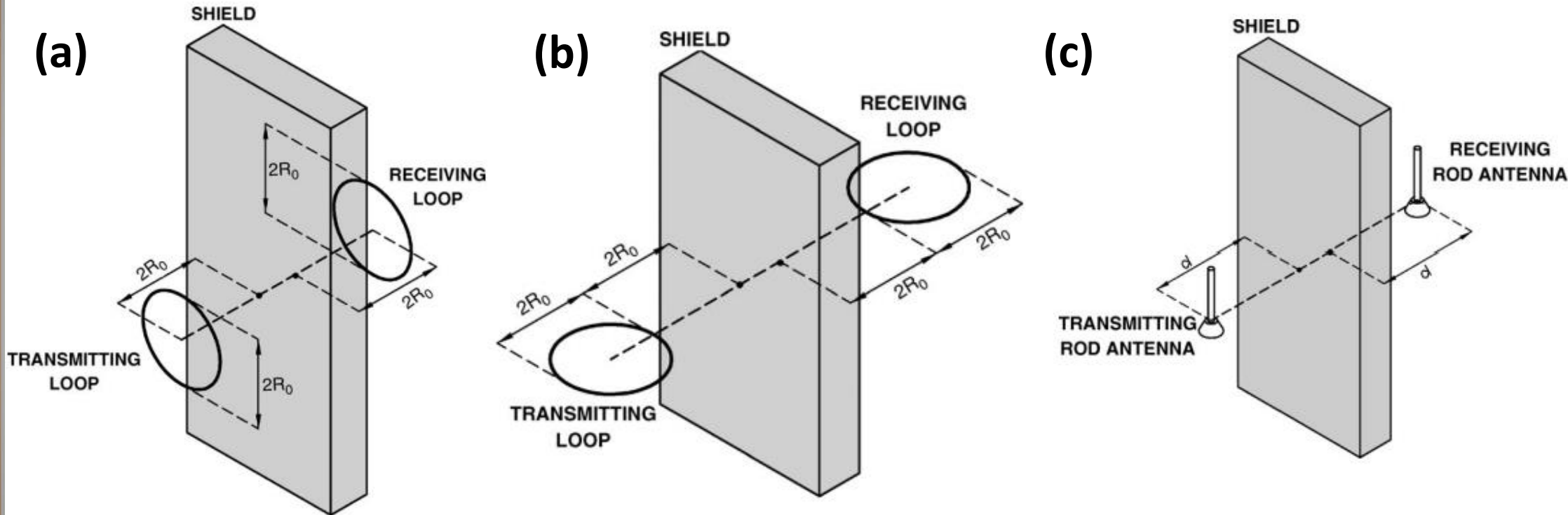


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Shielding Effectiveness Test Setup



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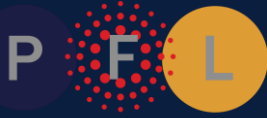


Shielding effectiveness set up based on the standard field source (a) magnetic field-NSA 65-6, (b) magnetic field-IEEE 299, and (c) electric field-IEEE 299

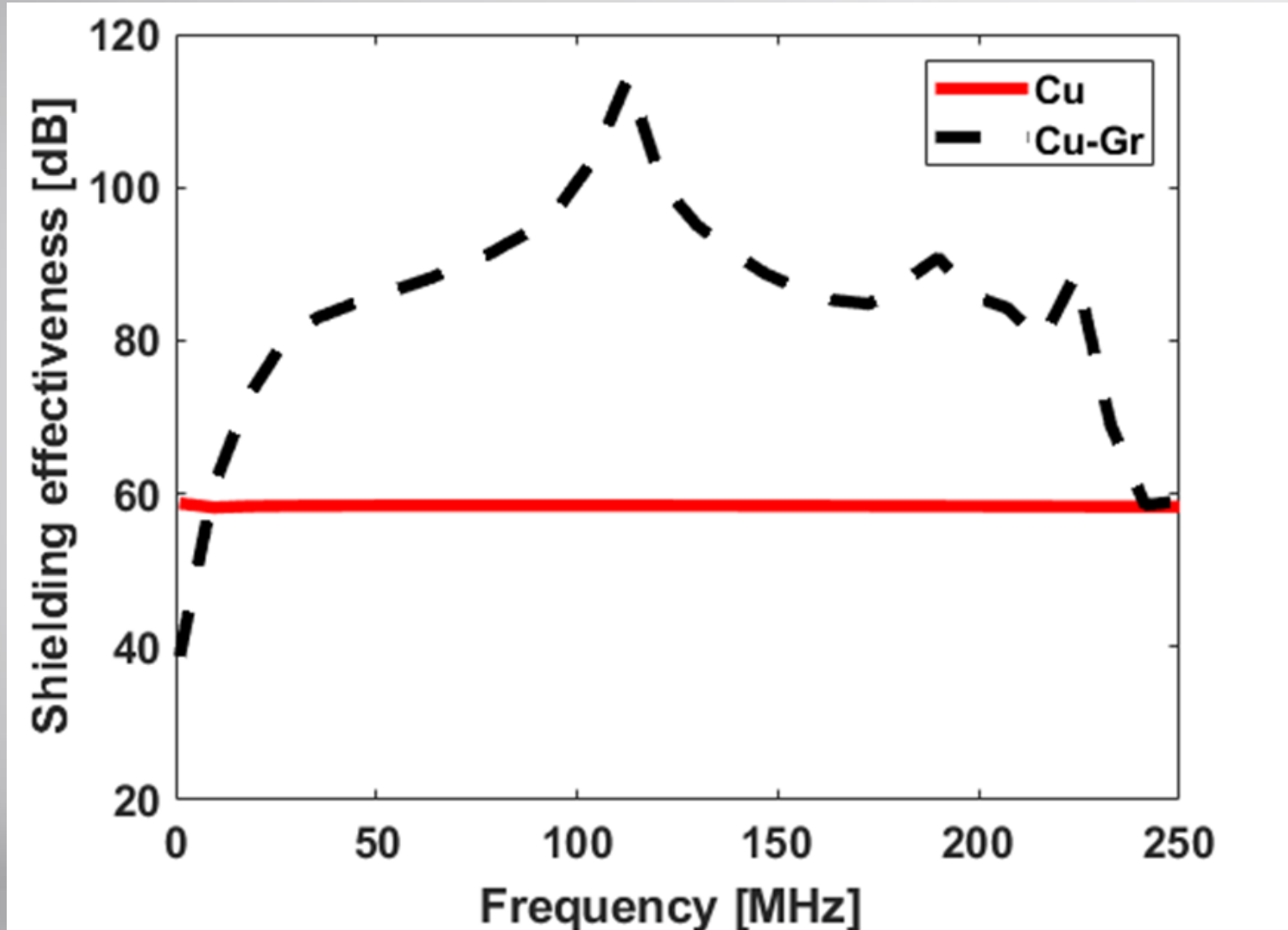
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$$SE = S_{21}(\text{with Shield}) - S_{21}(\text{w/o Shield})$$

Shielding Effectiveness of Cu-GrF structure

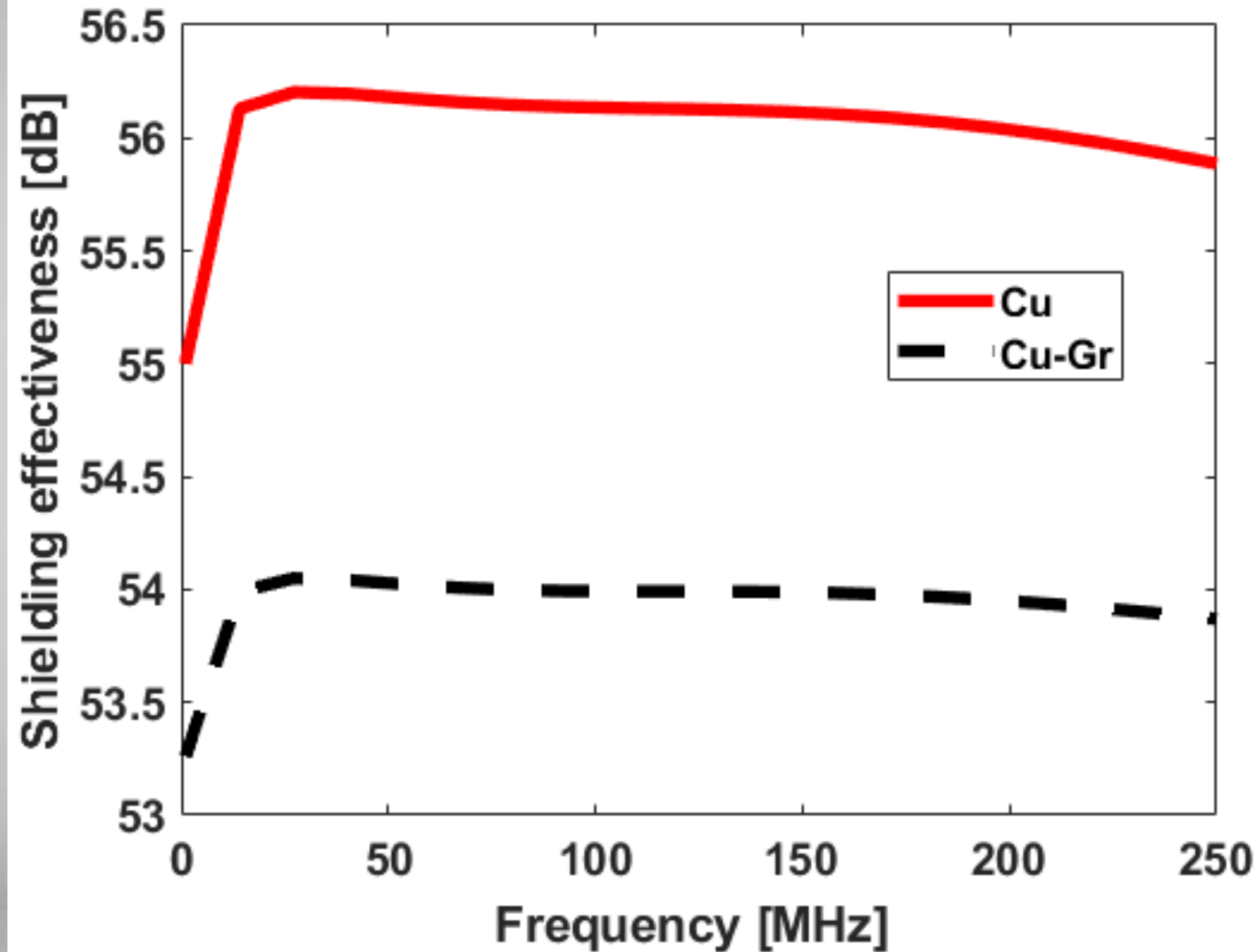


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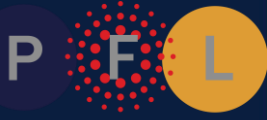
(a) Magnetic field-NSA 65-6

Shielding Effectiveness of Cu-GrF structure

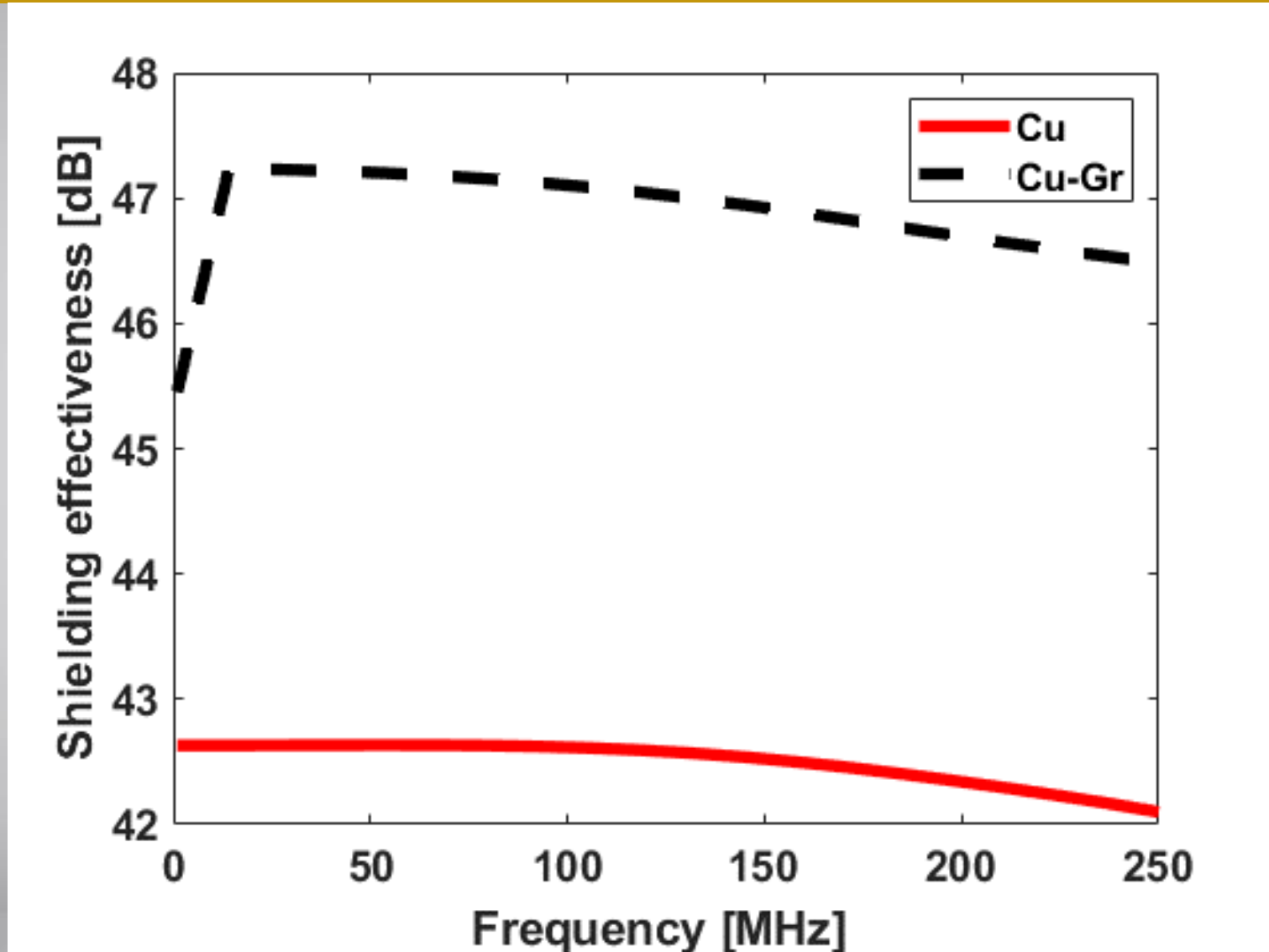


(b) Magnetic field-IEEE 299

Shielding Effectiveness of Cu-GrF structure



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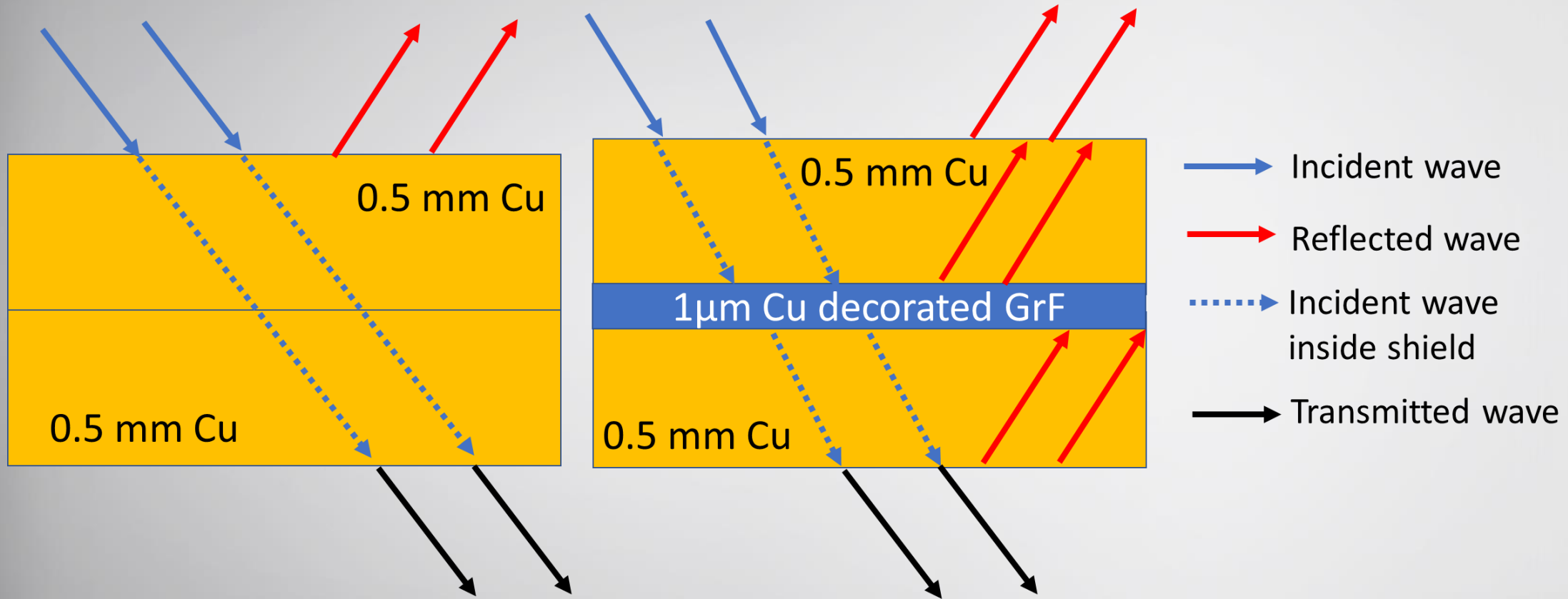


(c) Electric field-IEEE 299

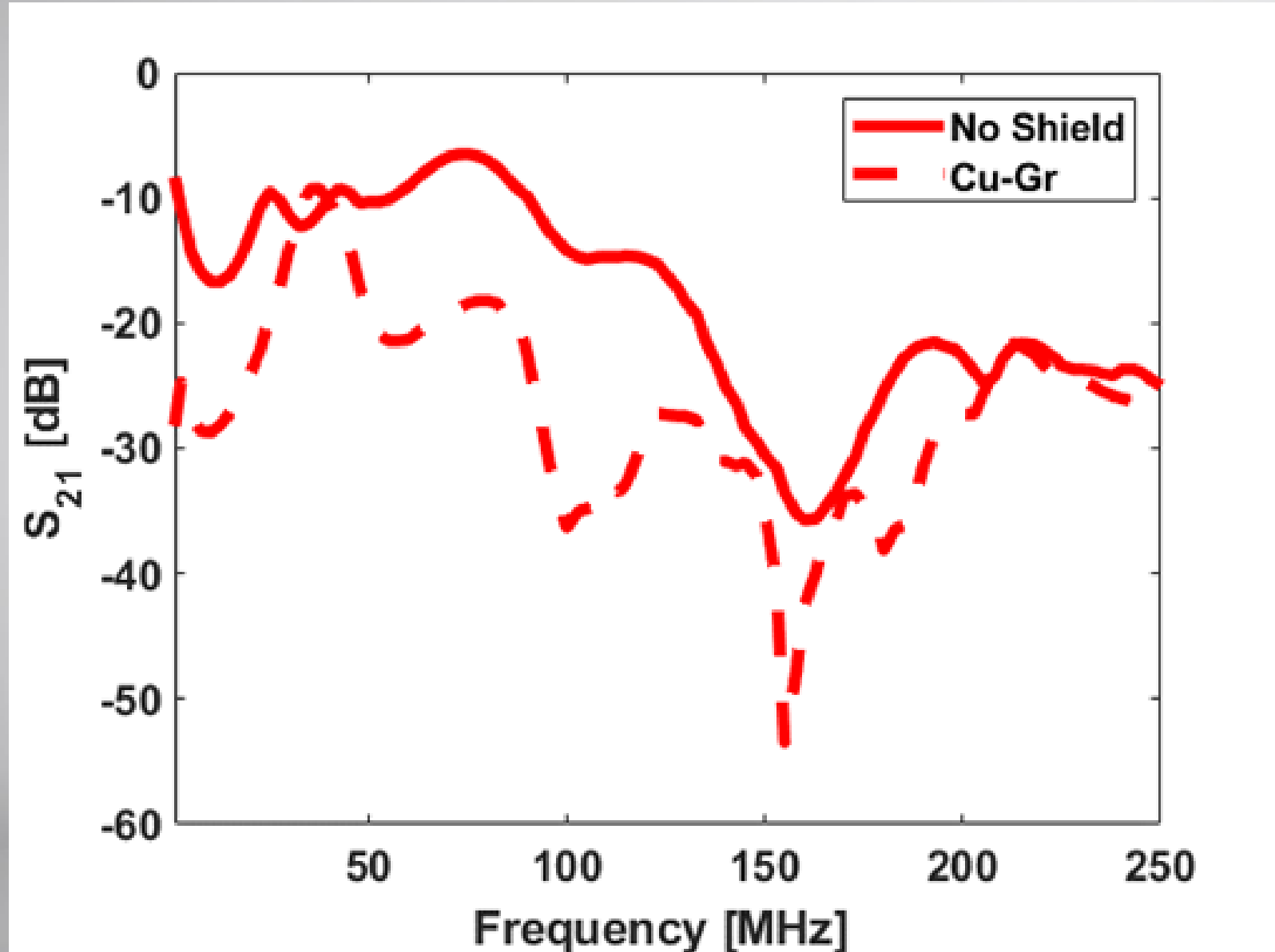
Shielding Effectiveness mechanism in Cu-GrF structure



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Shielding Effectiveness measurements with NSA 65-6 standard



Conclusions

Successful fabrication of layered Cu-GrF structure by SPS.

Dense Microstructure → SPS with Pressure

Porous Microstructure → SPS without Pressure

Strong Cu-GrF bonding irrespective of pressure and pressureless-sintering.

As per NSA 65-6 standard, SE is

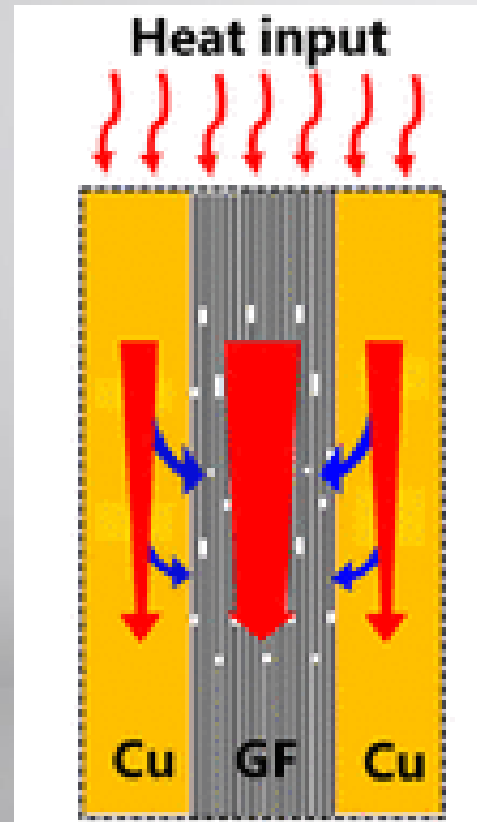
Cu sample: 60 dB

Cu-GrF: 40-120 dB

Future Directions

Multi-layered Cu-GrF structure fabrication by SPS.

Electrical and Thermal Conductivity measurements of Cu-GrF structure



Acknowledgments

FIU | Advanced Materials
Engineering Research
Institute
FLORIDA INTERNATIONAL UNIVERSITY

Thank You For Your Attention!